

FIG. 1

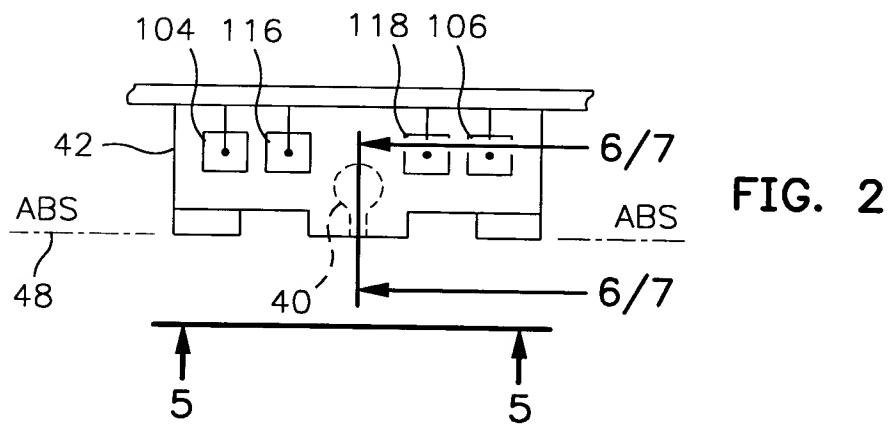


FIG. 2

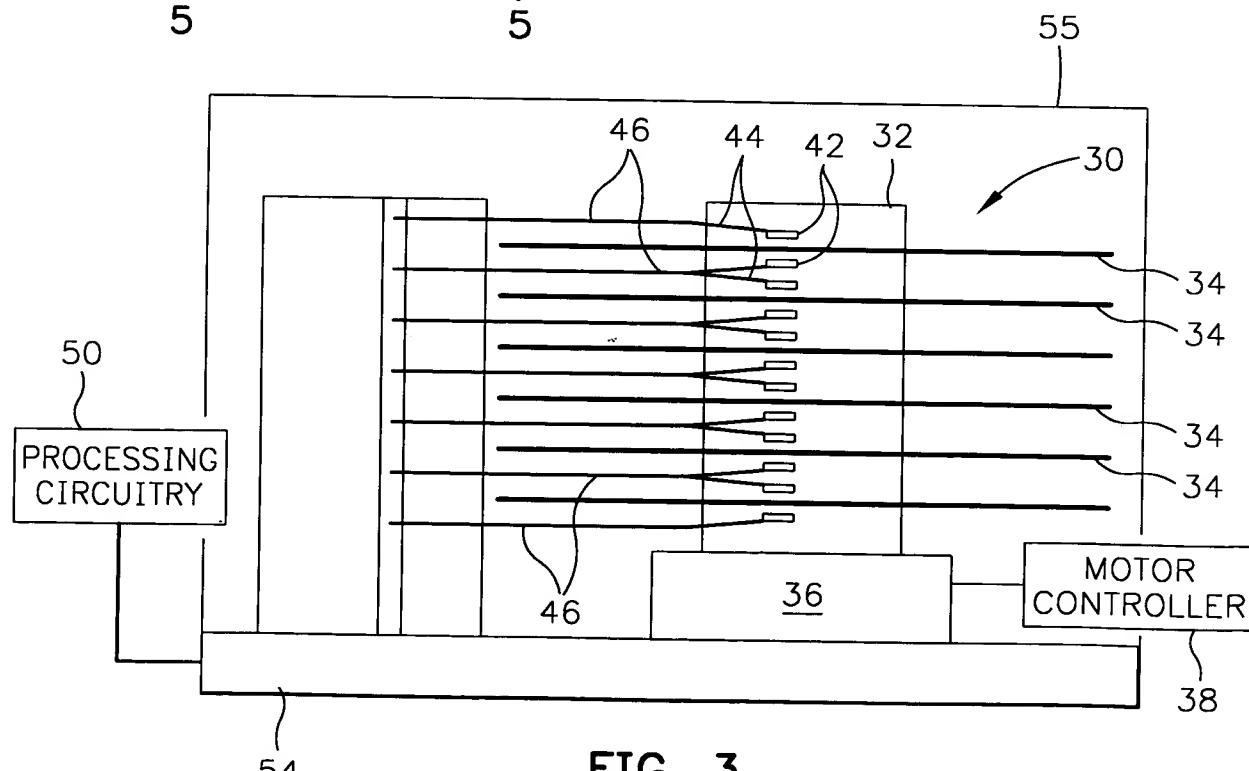


FIG. 3

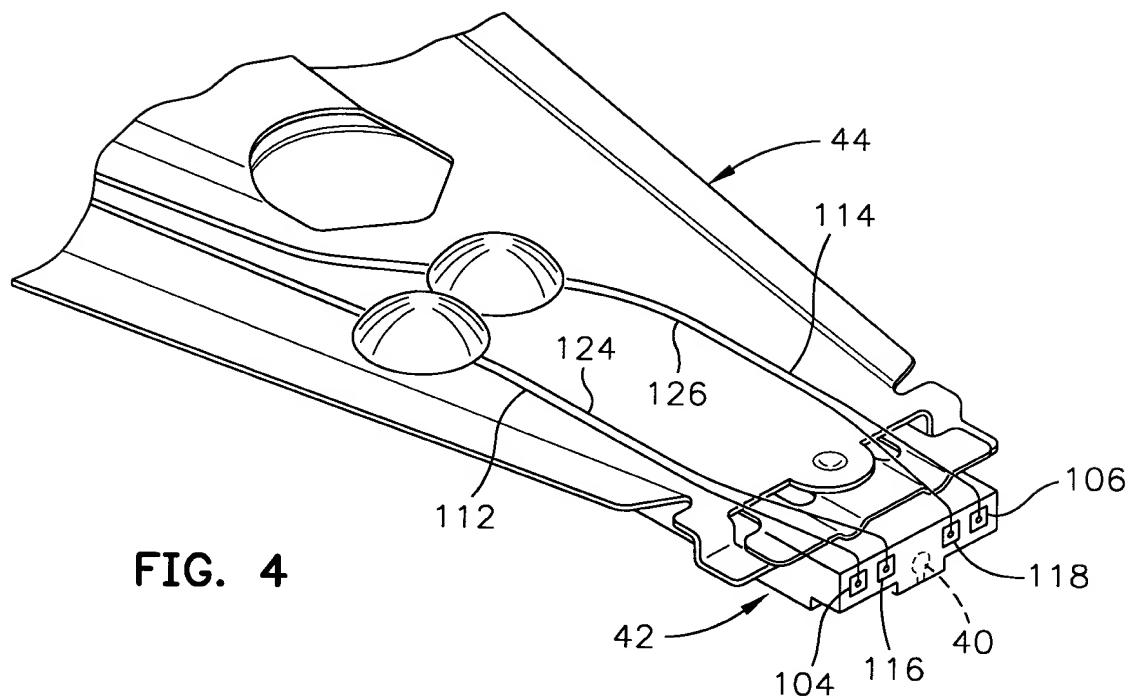


FIG. 4

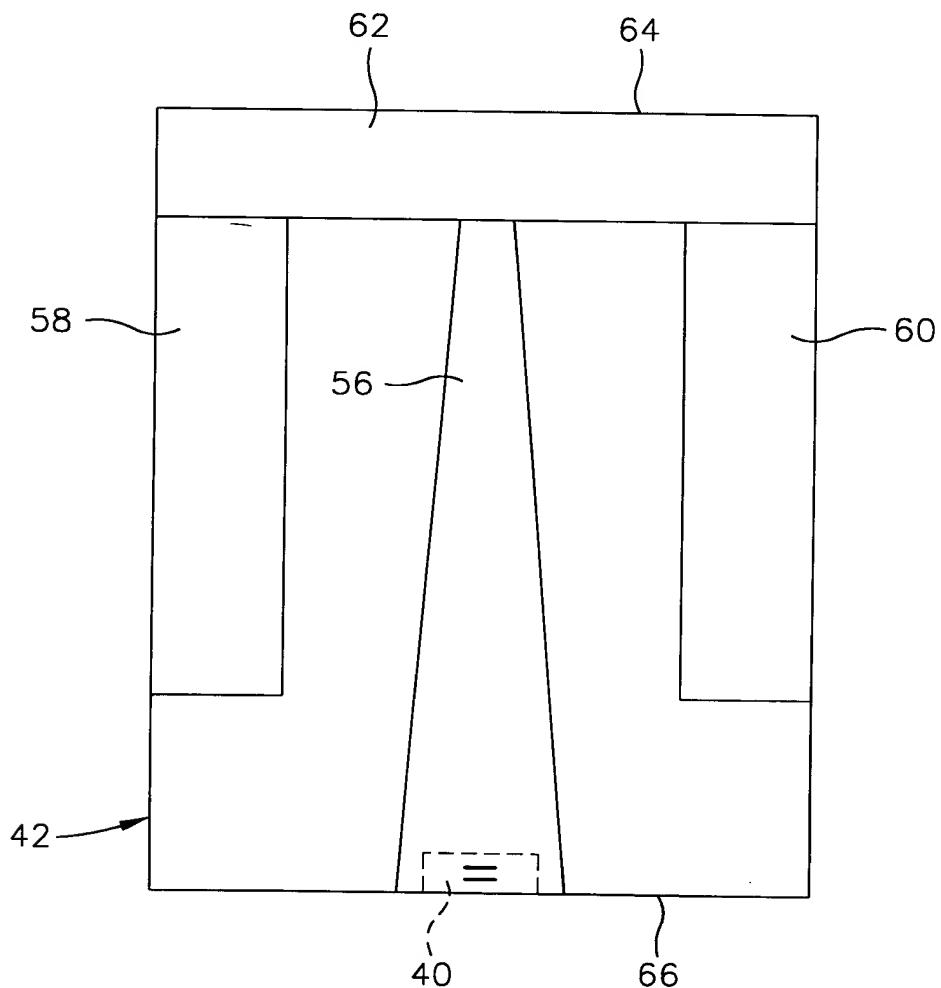


FIG. 5

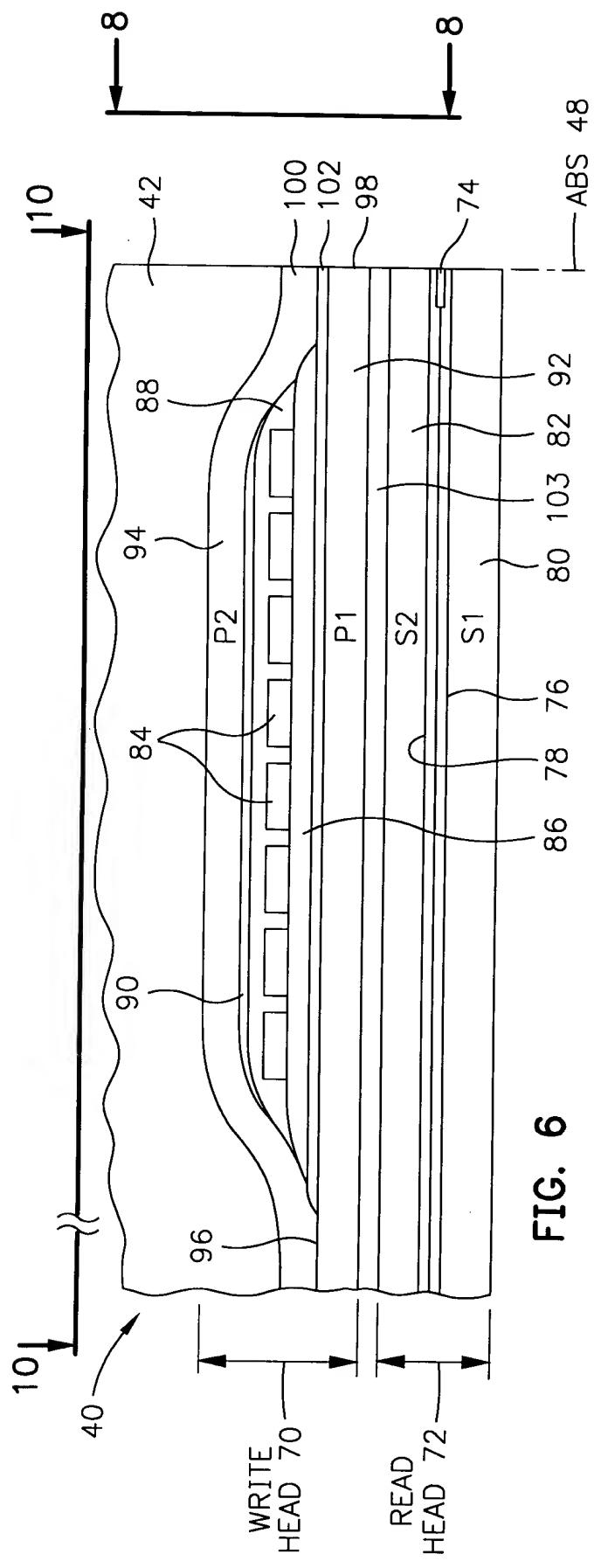


FIG. 6

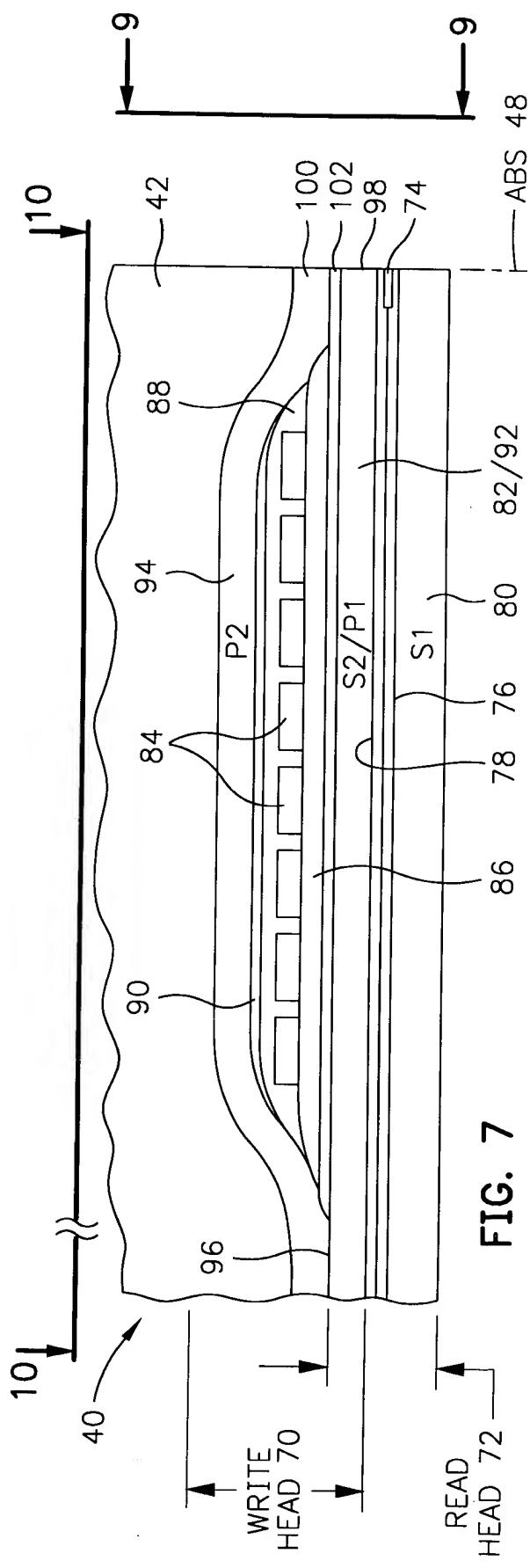


FIG. 7

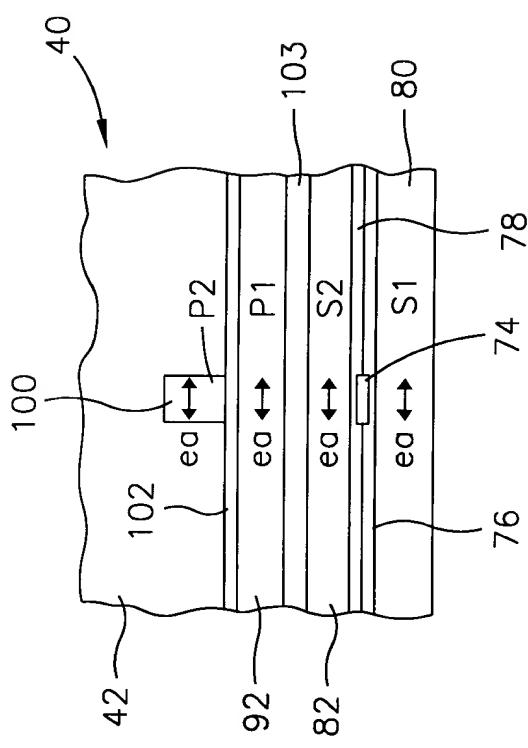


FIG. 8

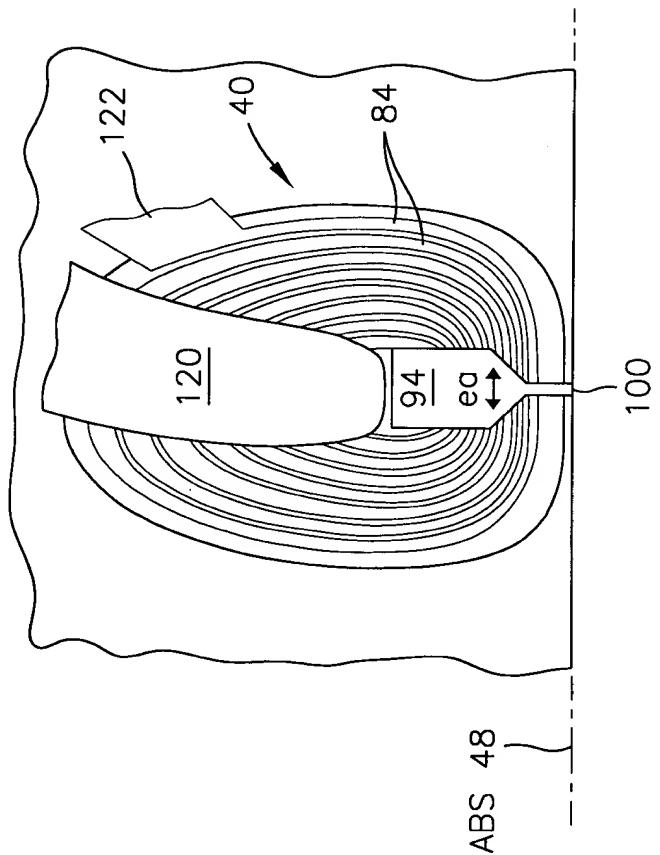


FIG. 10

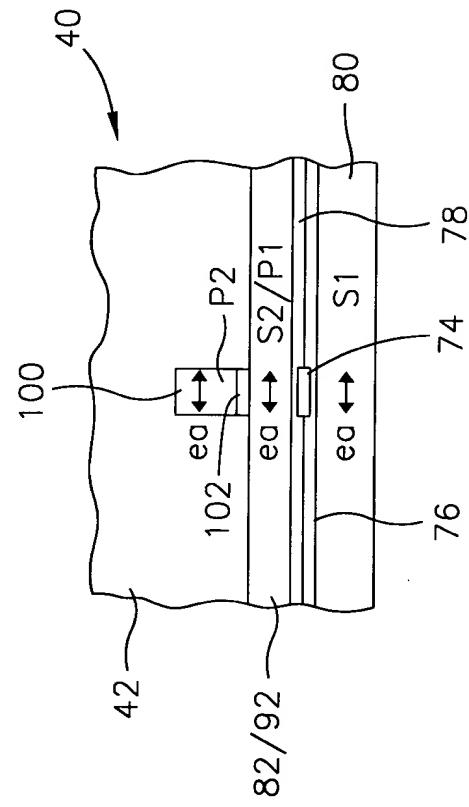


FIG. 9

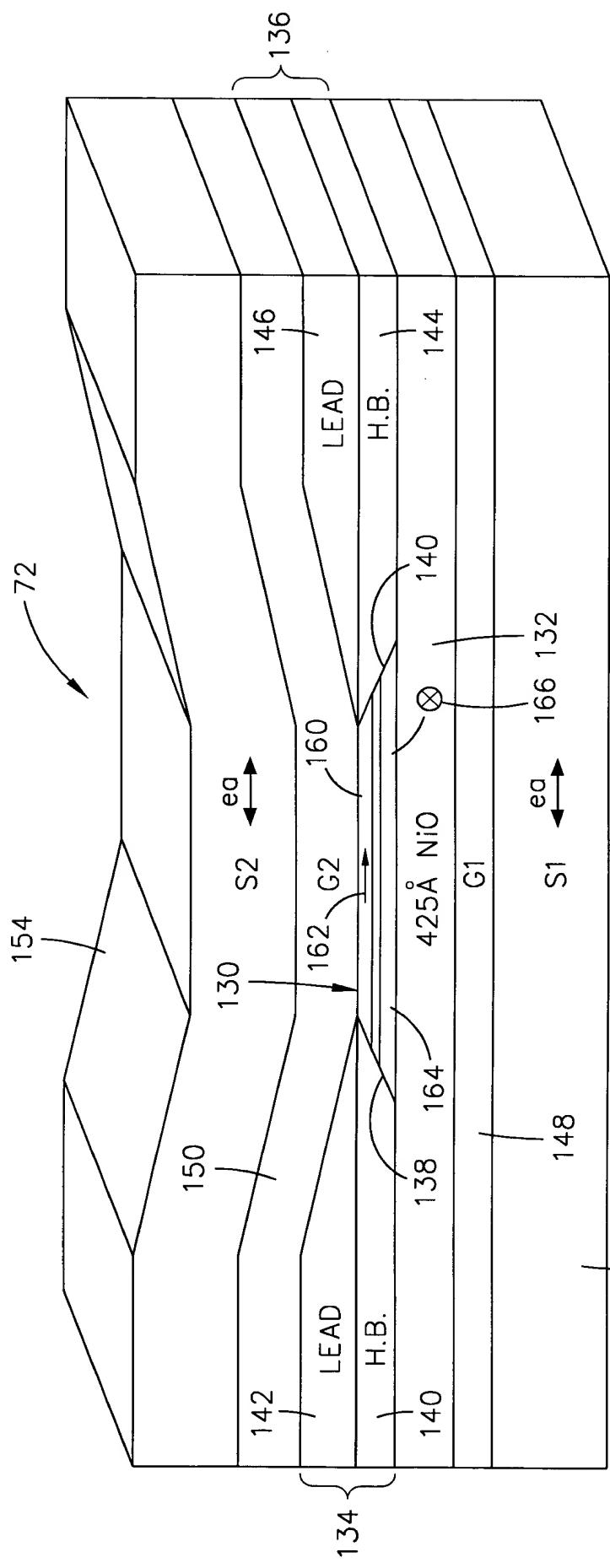


FIG. 11
(ABS)

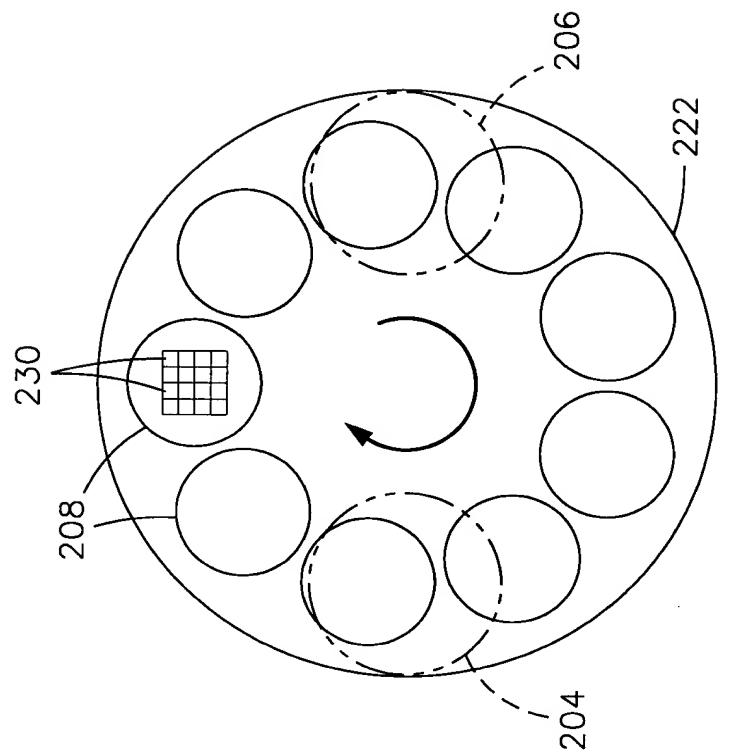


FIG. 13

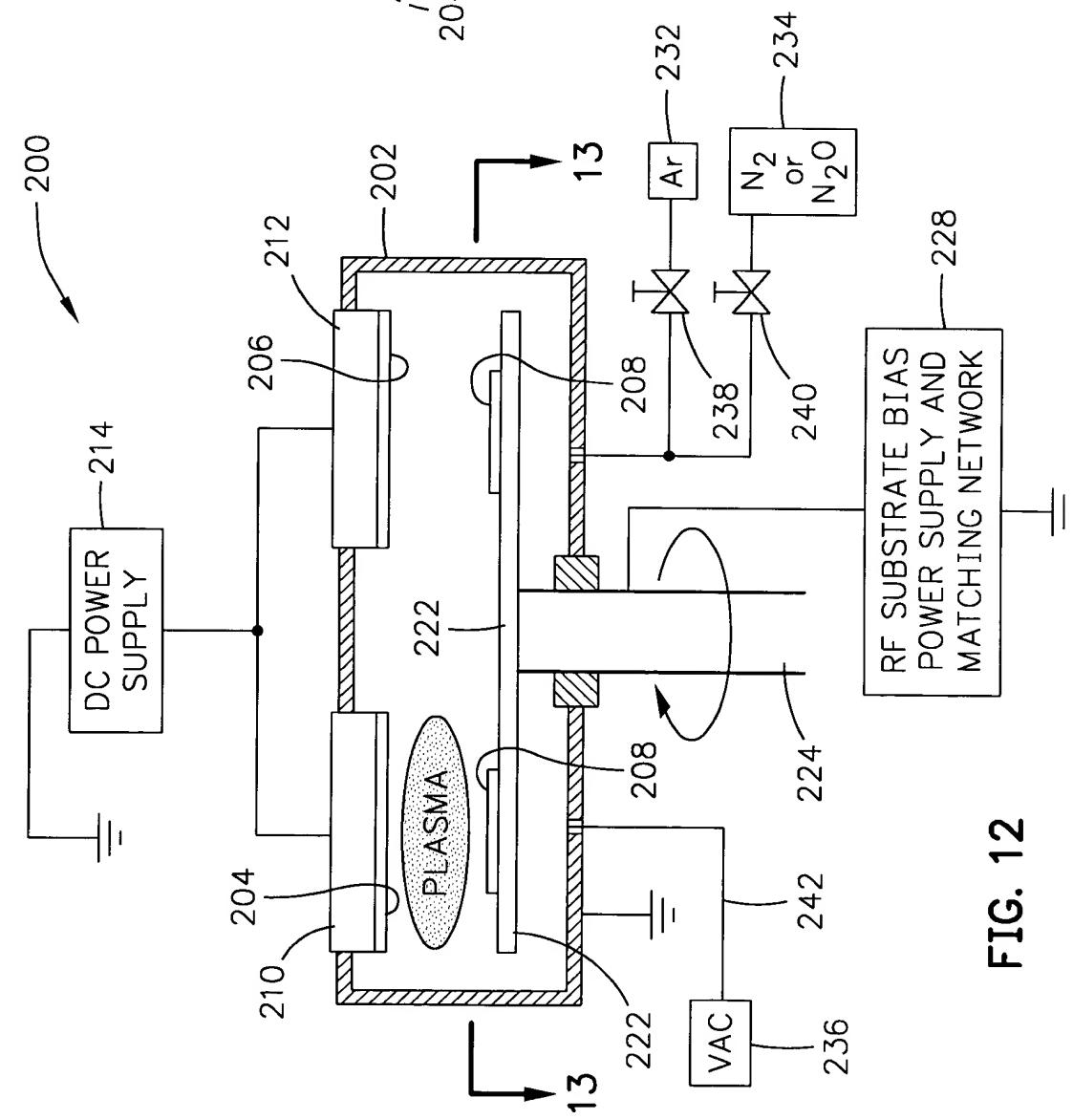


FIG. 12

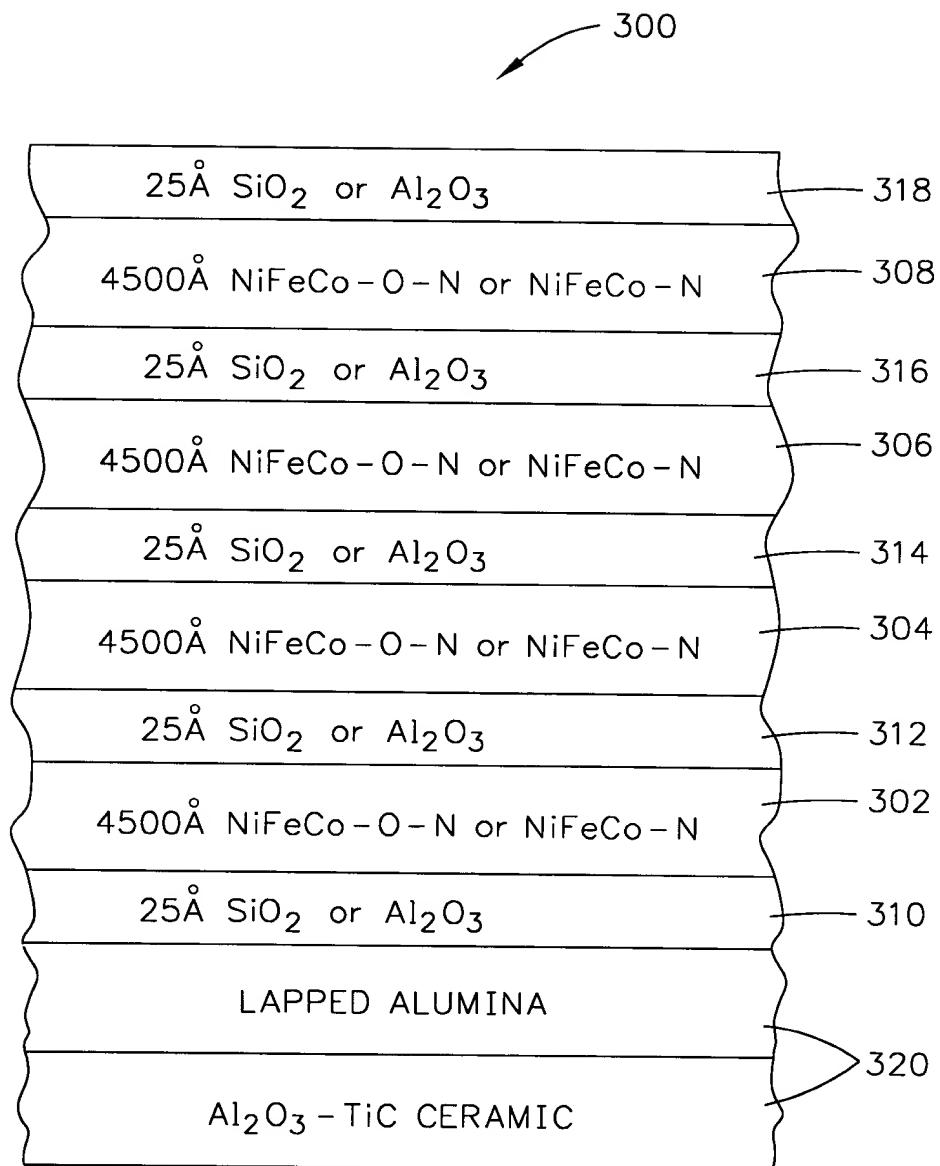


FIG. 14

FIG. 15

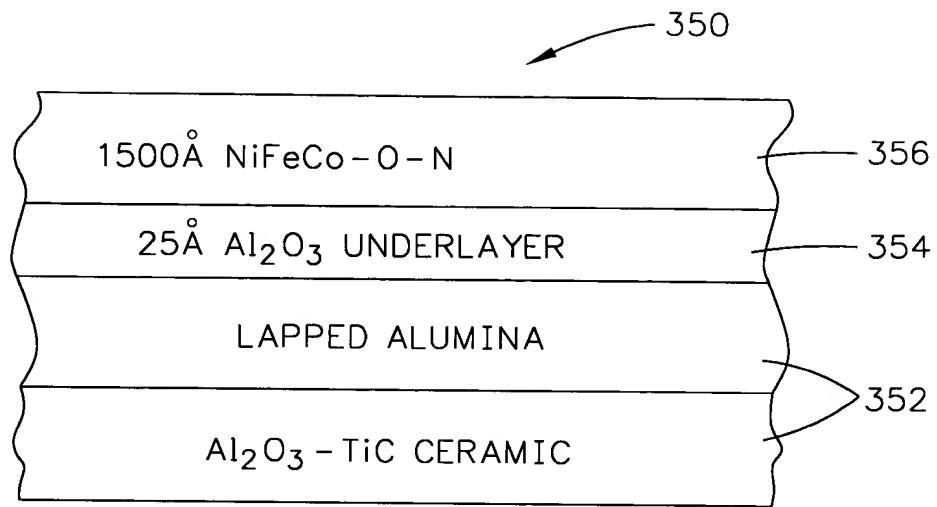


FIG. 16

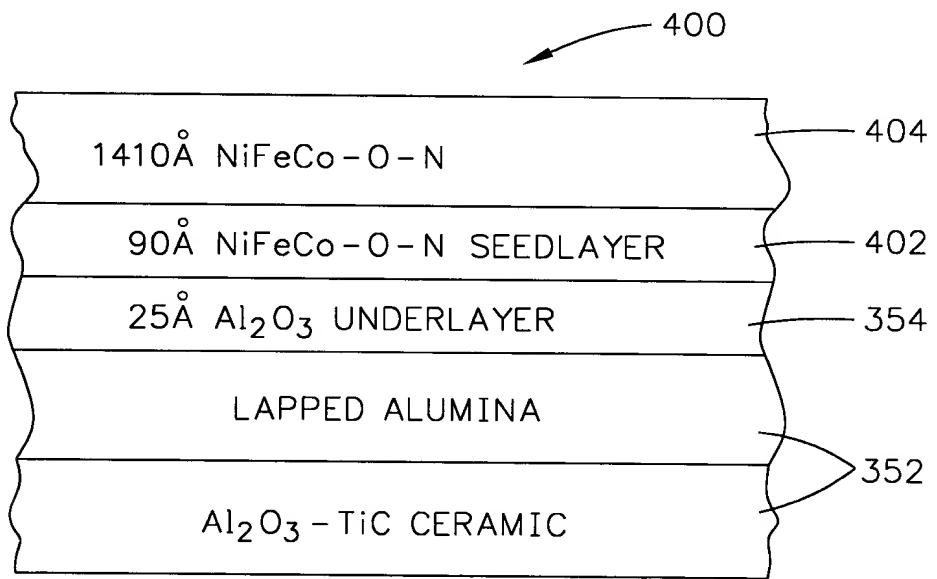
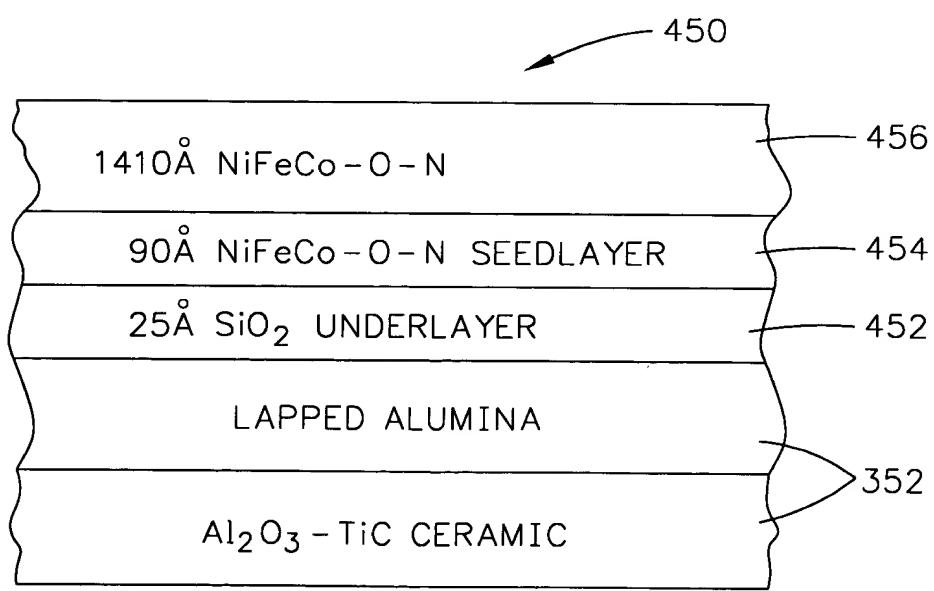
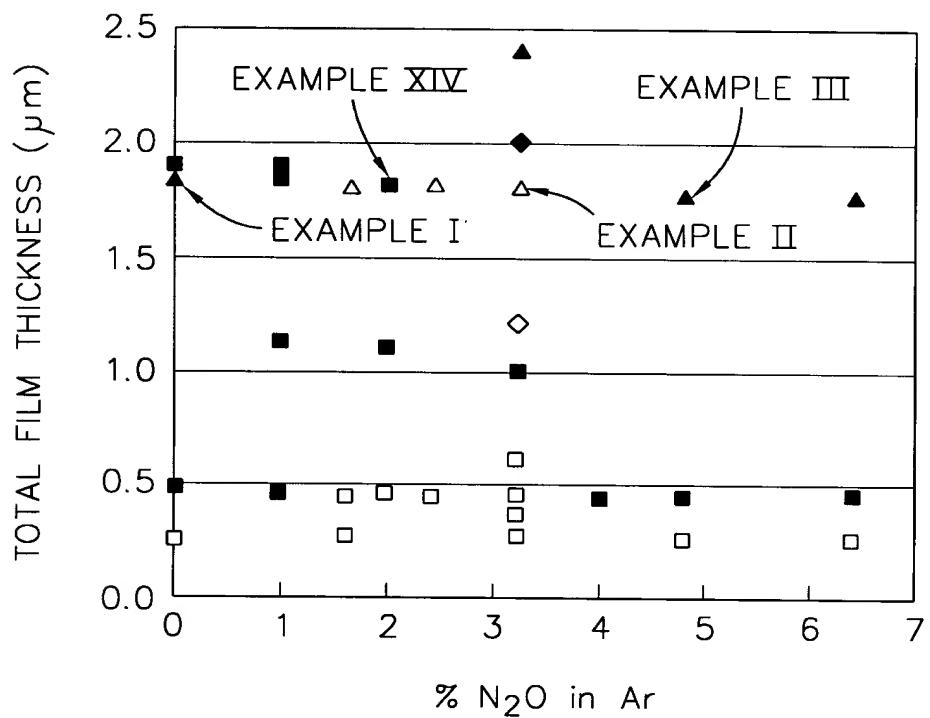


FIG. 17



THICKNESS AND N_2O CONCENTRATION
 DEPENDENCE OF IN-PLANE AND VERTICAL H_k IN
 SINGLE LAYER AND LAMINATED NiFeCo-O-N FILMS
 (DC MAG 1750 W, 2.0×10^{-3} mbar, NO BIAS)



- SINGLE LAYER FILMS - IN PLANE H_k
- ◊ 2X LAMINATED FILMS - IN PLANE H_k
- △ 4X LAMINATED FILMS - IN PLANE H_k
- SINGLE LAYER FILMS - VERTICAL H_k
- ◆ 2X LAMINATED FILMS - VERTICAL H_k
- ▲ 4X LAMINATED FILMS - VERTICAL H_k

FIG. 18

THICKNESS AND N_2 CONCENTRATION
DEPENDENCE OF IN-PLANE AND VERTICAL H_k IN
SINGLE LAYER AND LAMINATED NiFeCo-N FILMS
(DC MAG 1750 W, 2.0×10^{-3} mbar, NO BIAS)

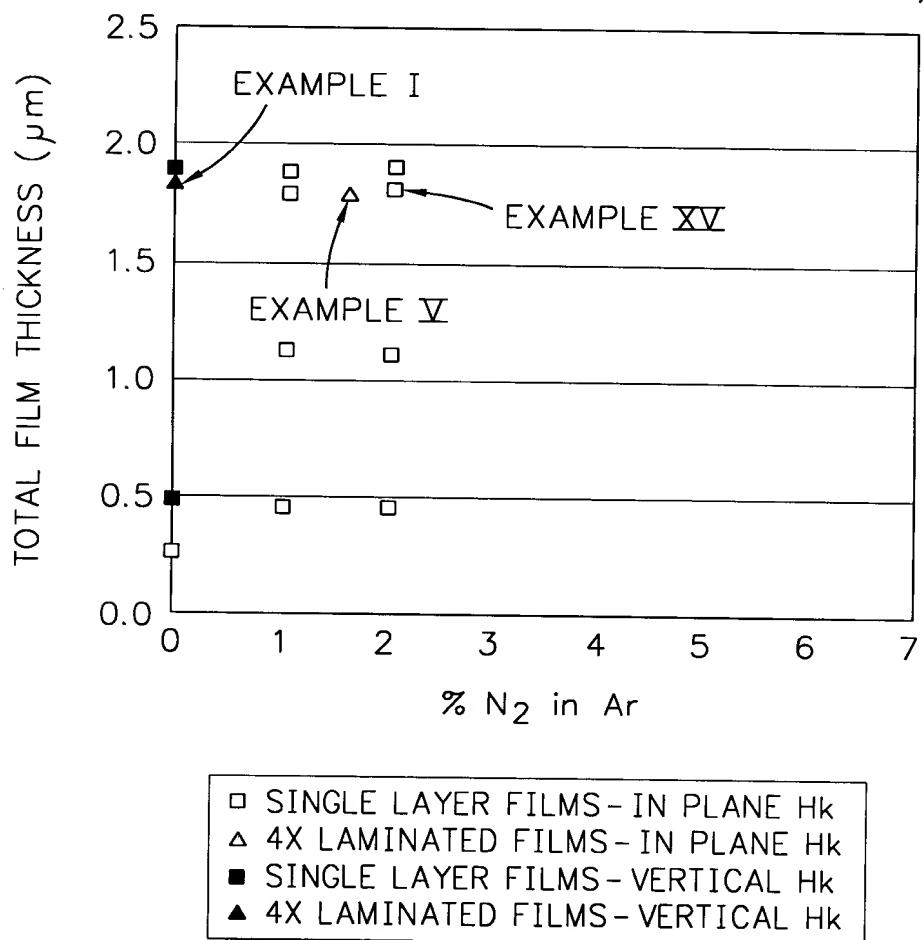


FIG. 19

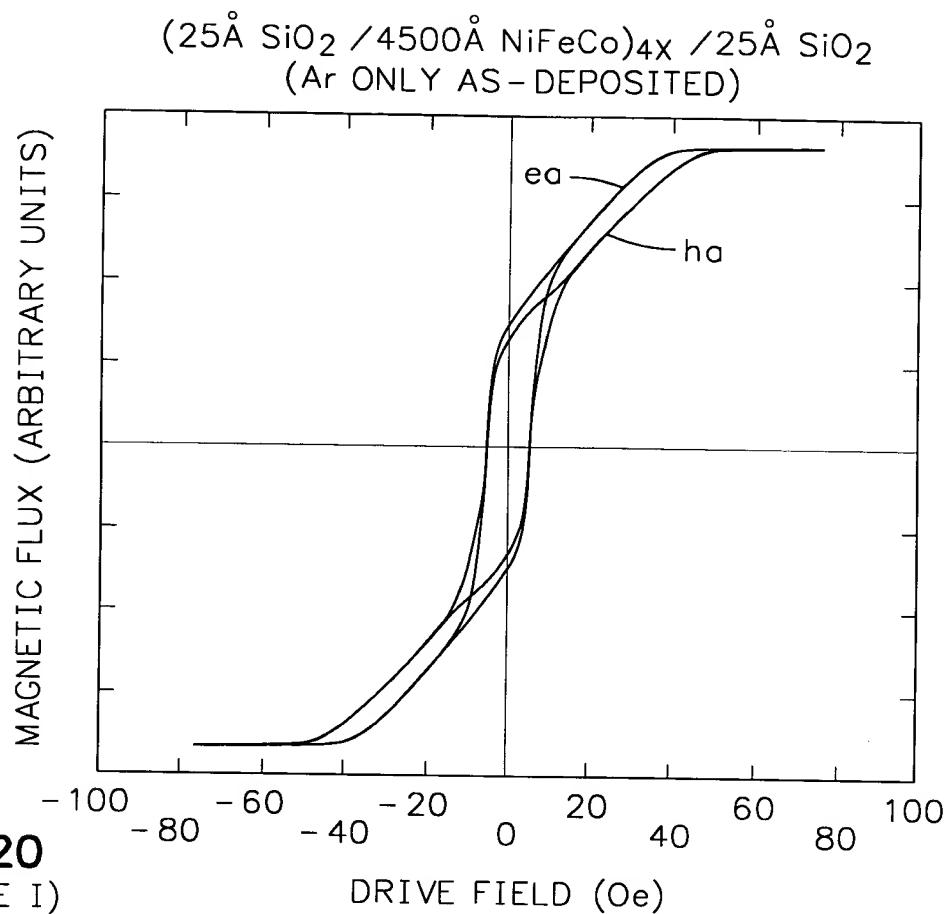


FIG. 20
(EXAMPLE I)

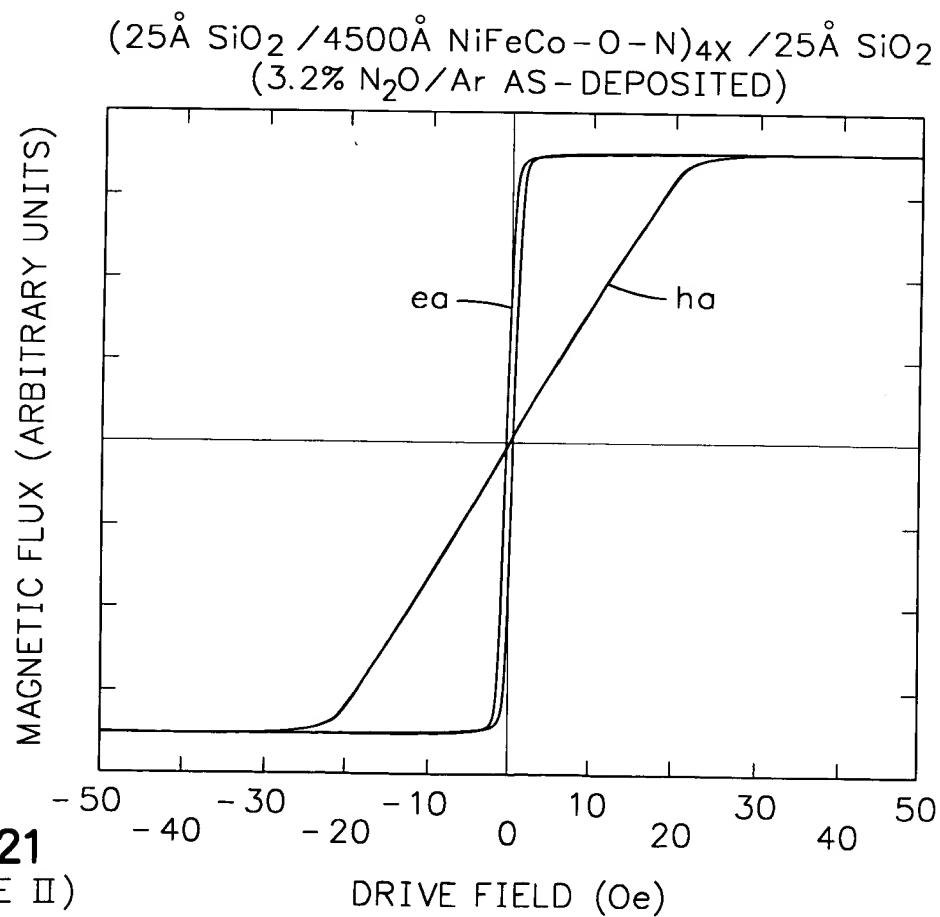


FIG. 21
(EXAMPLE II)

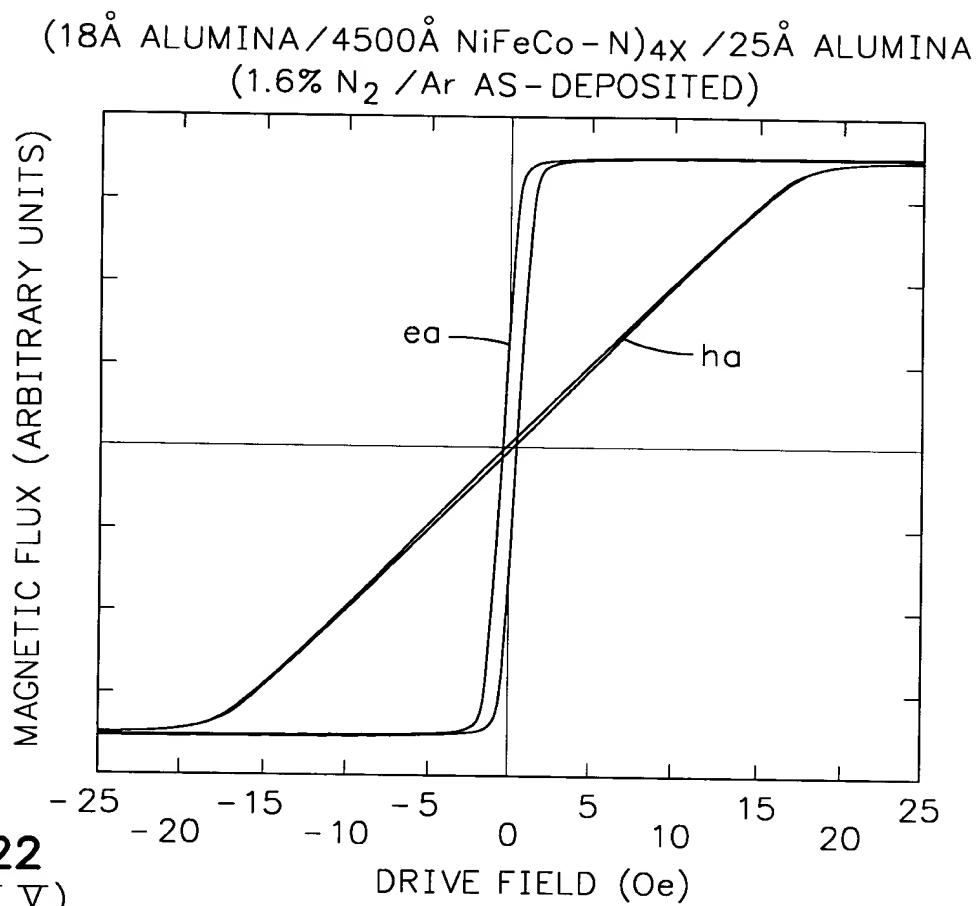


FIG. 22
(EXAMPLE IV)

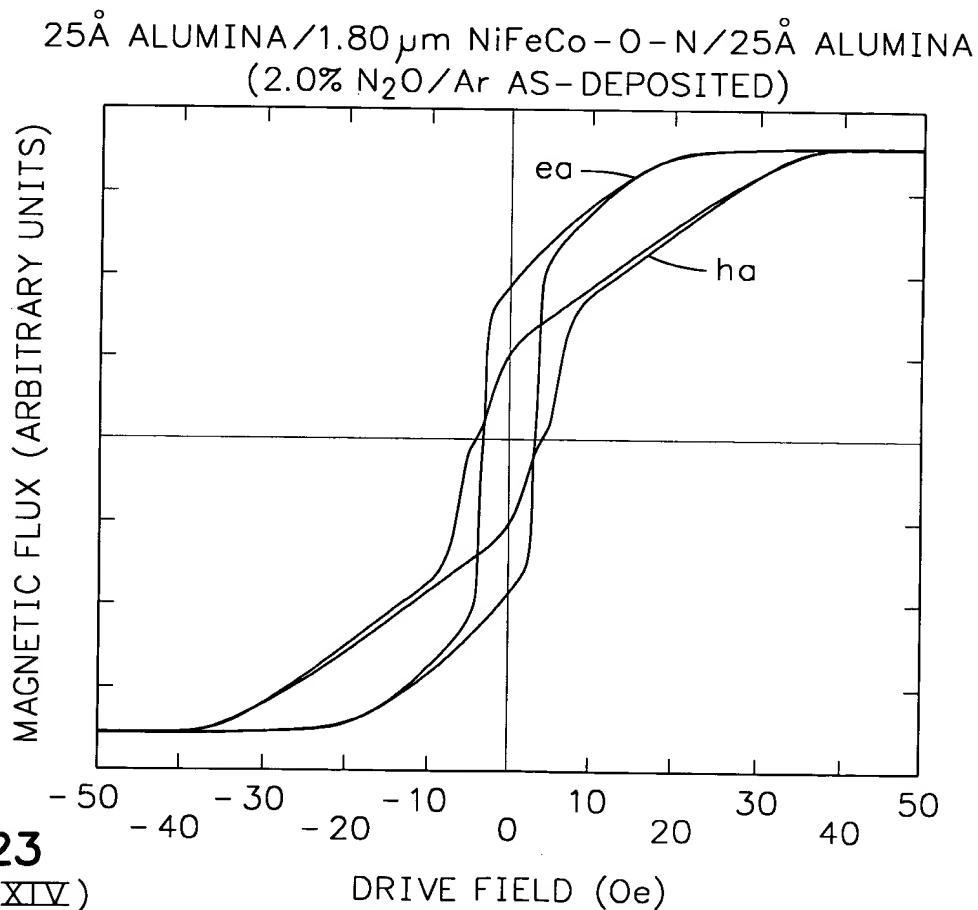


FIG. 23
(EXAMPLE XIV)

25 \AA ALUMINA / 1.80 μm NiFeCo - N / 25 \AA ALUMINA
(2.0% N₂ / Ar AS-DEPOSITED)

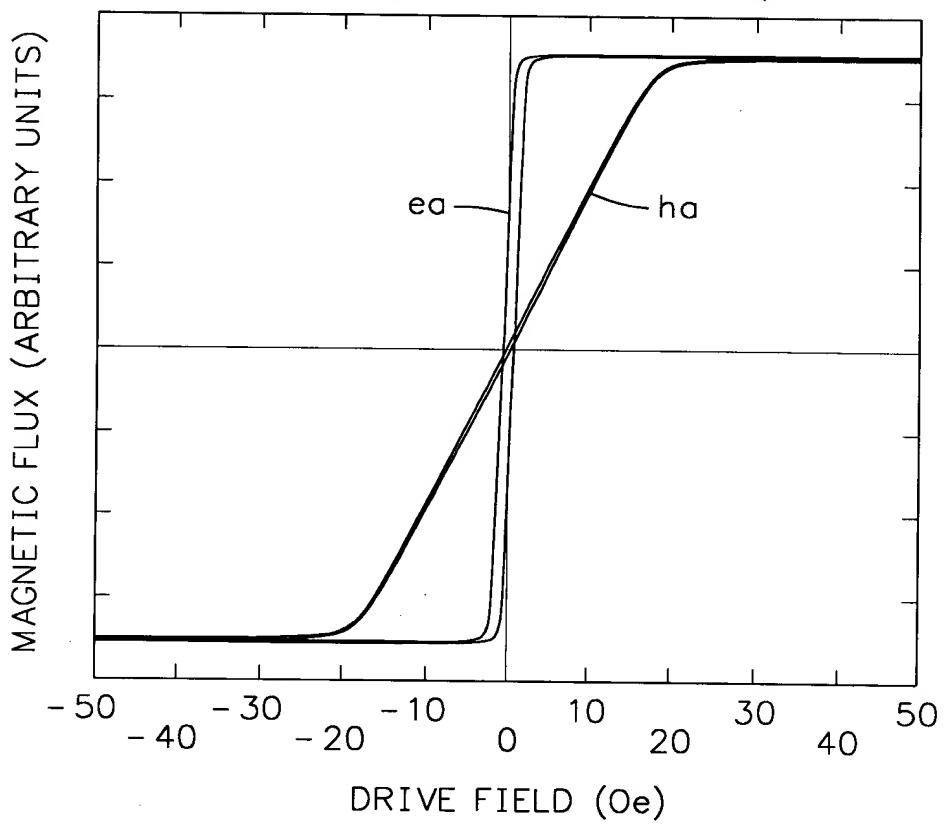


FIG. 24
(EXAMPLE XXV)

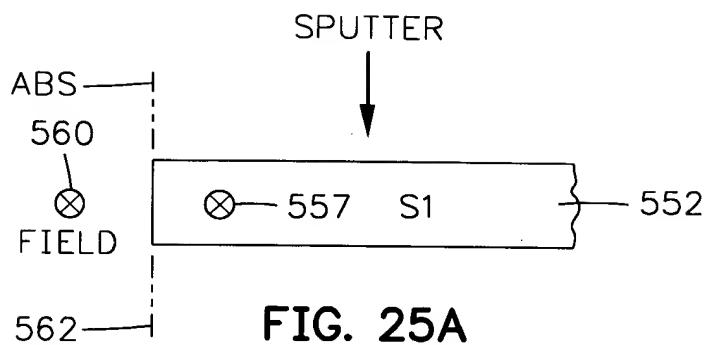


FIG. 25A

ANNEAL S1 (270°C)

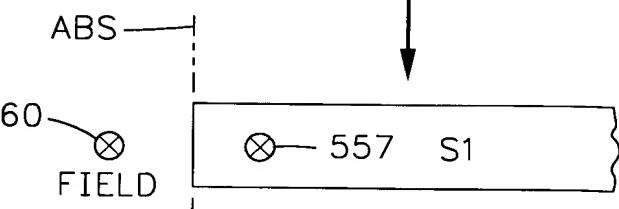


FIG. 25B

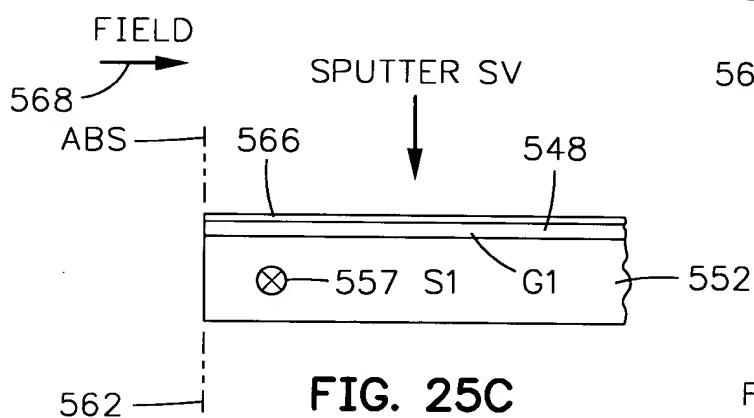


FIG. 25C

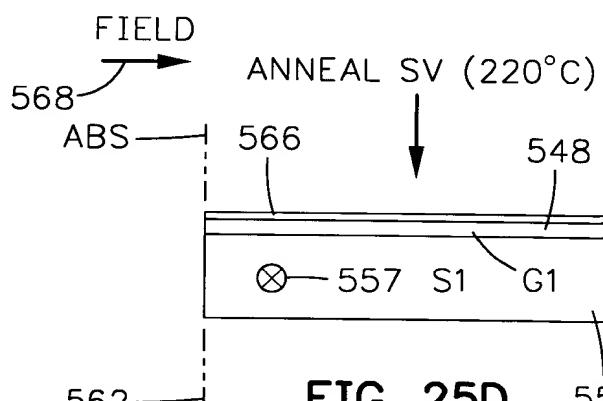


FIG. 25D

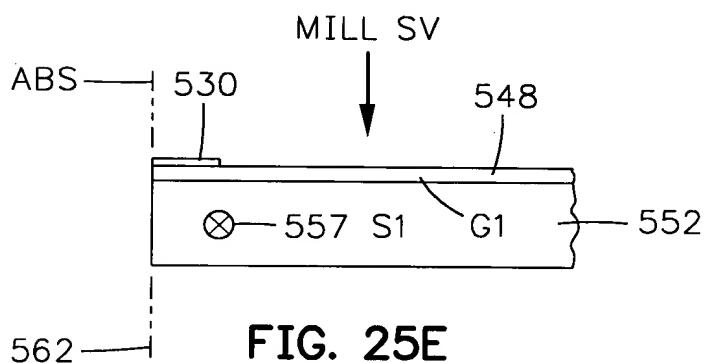


FIG. 25E

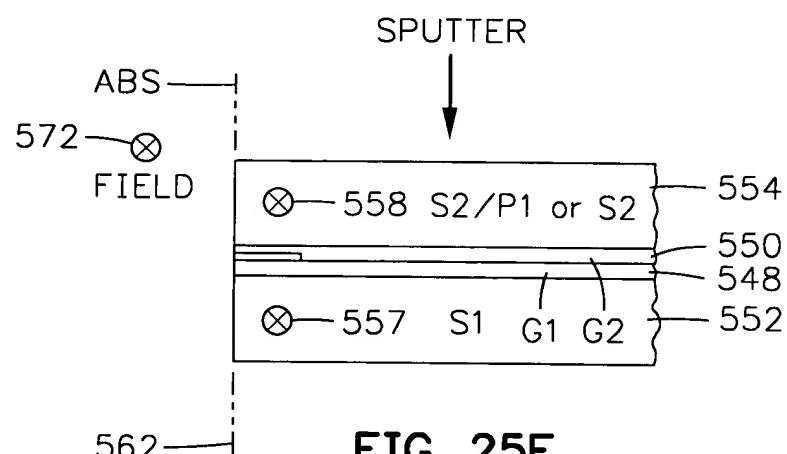


FIG. 25F

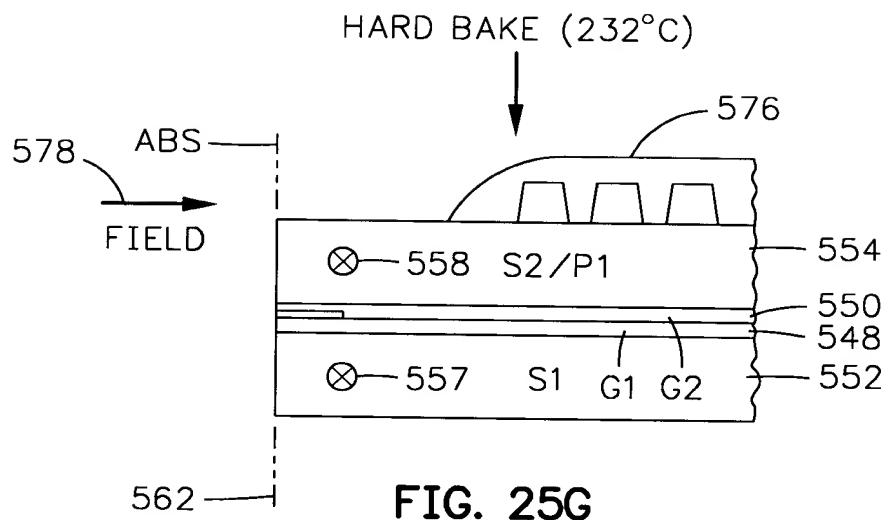


FIG. 25G

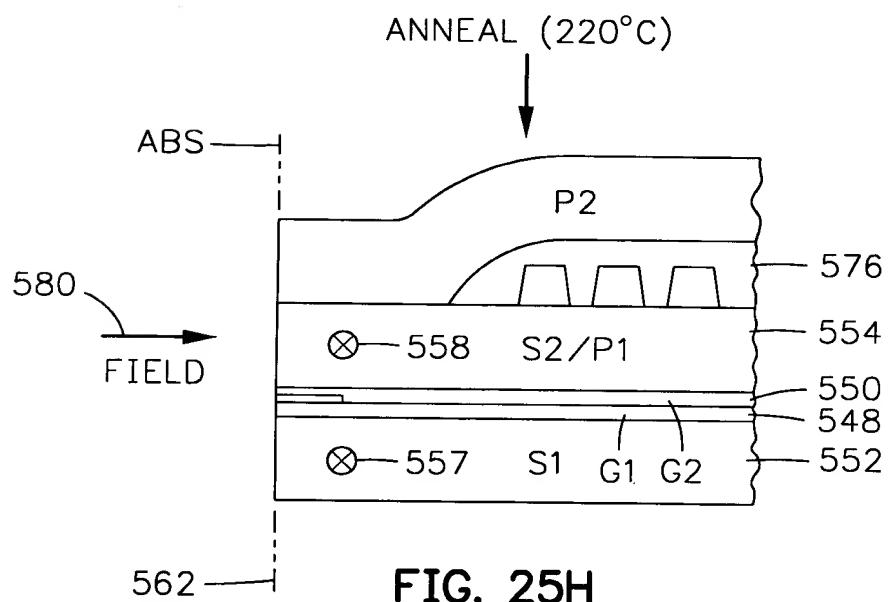


FIG. 25H

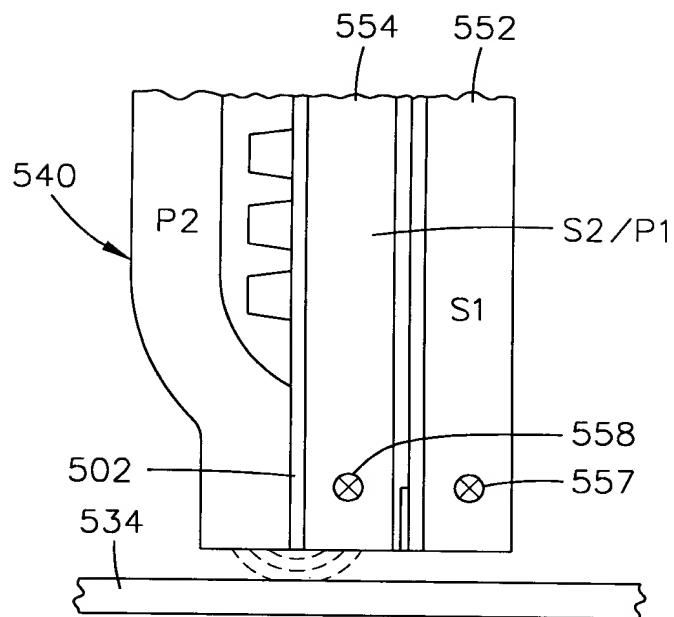


FIG. 26

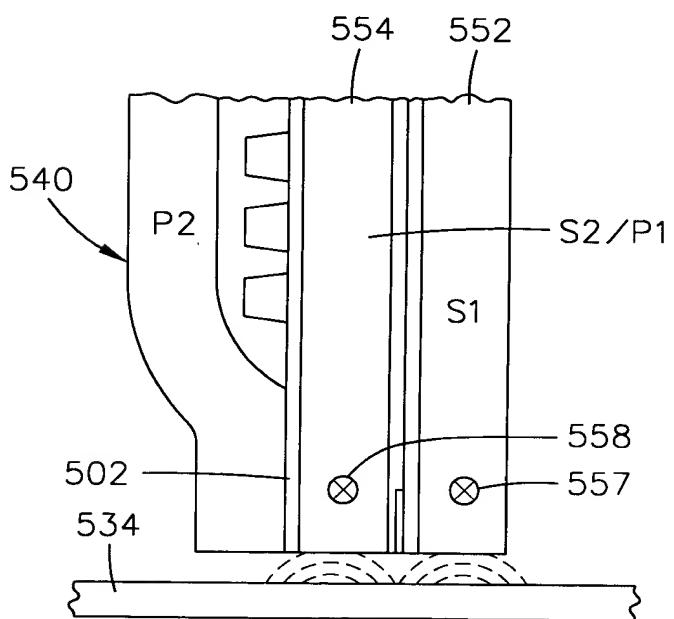


FIG. 27

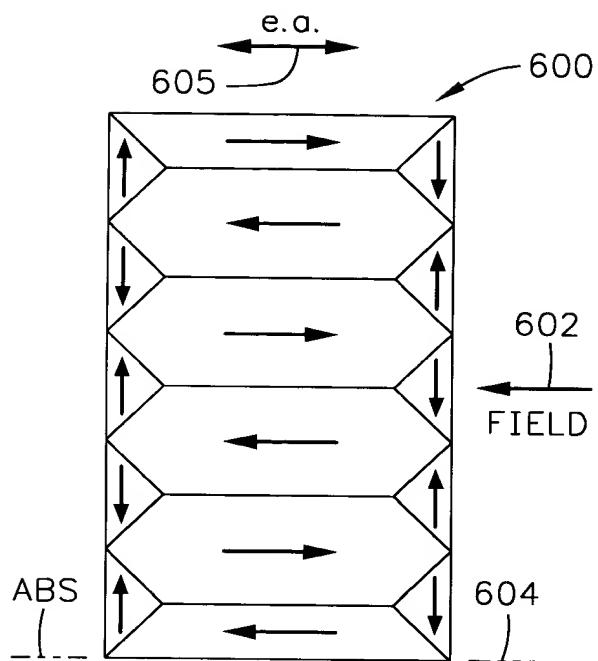


FIG. 28A
(PRIOR ART)

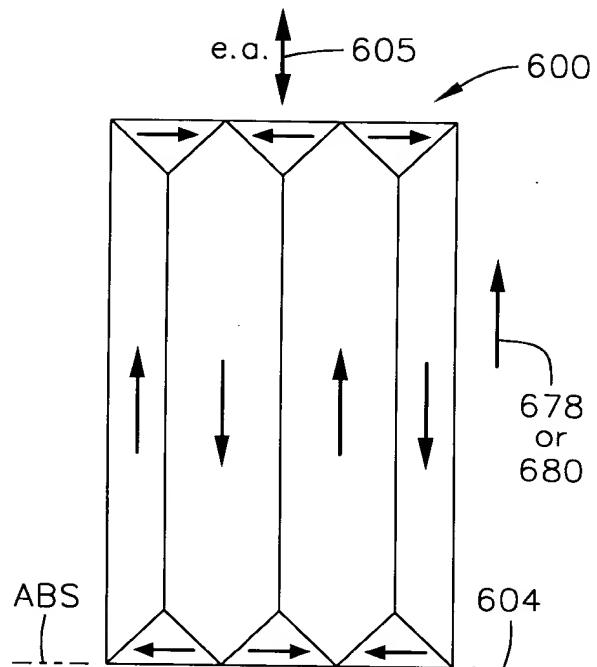


FIG. 28B
(PRIOR ART)

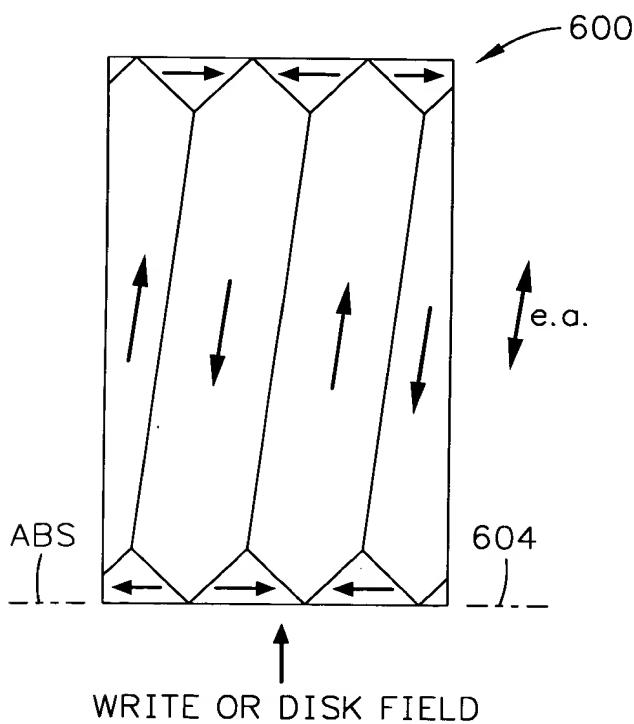


FIG. 28C
(PRIOR ART)

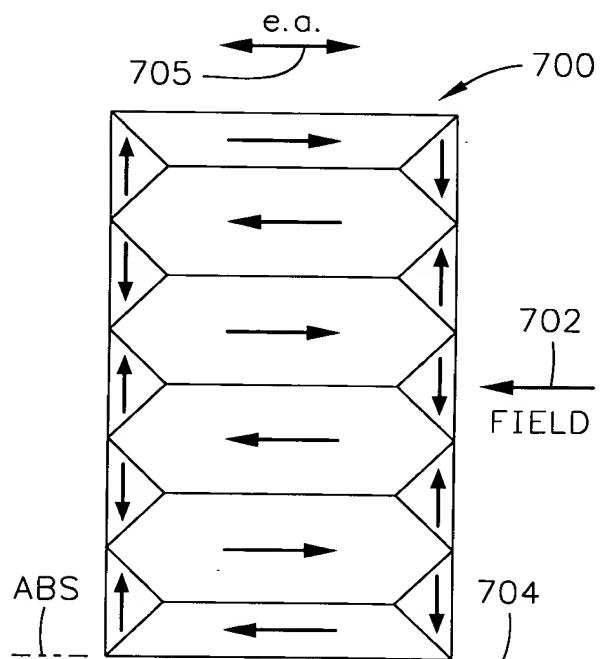


FIG. 29A

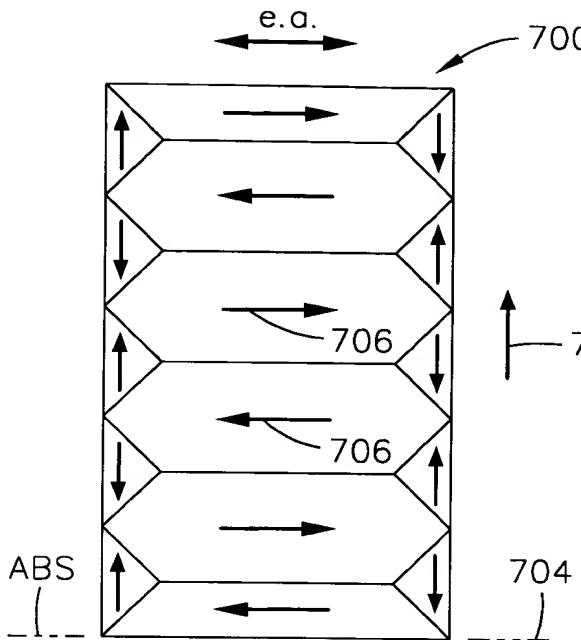


FIG. 29B
NiFeCo[-O]-N AFTER HARDBAKE
ANNEALING OR RESETTING
IN THE PRESENCE OF A FIELD
PERPENDICULAR TO THE ABS

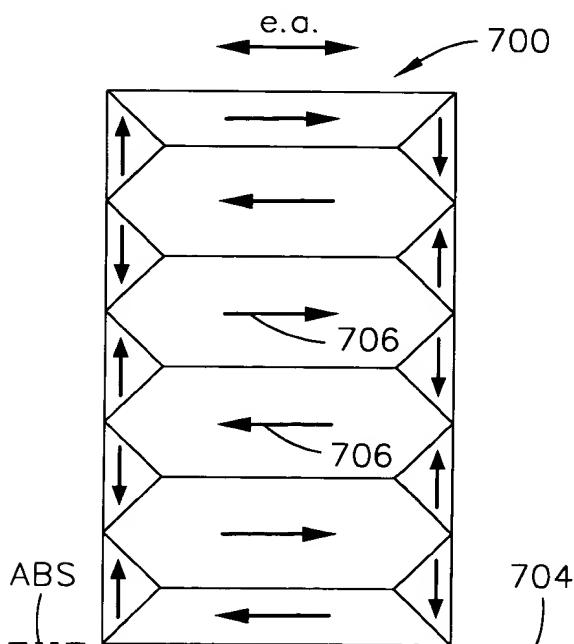
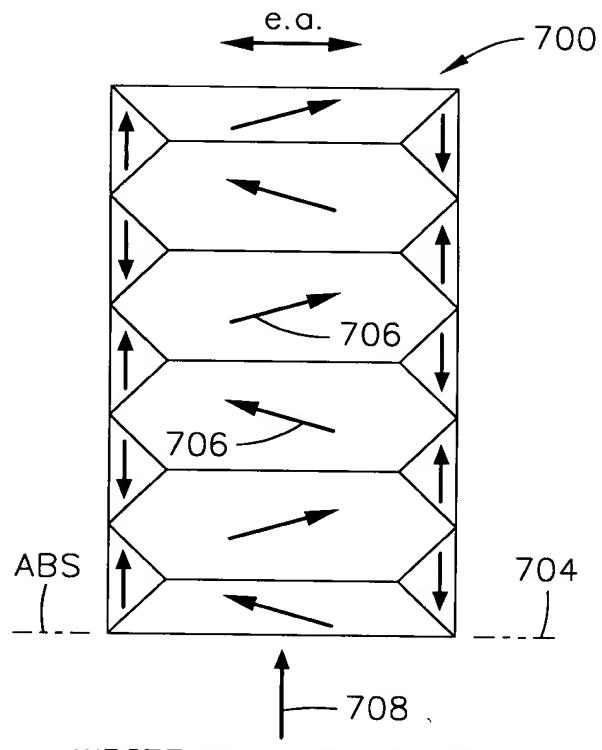


FIG. 29D